



**International
Standard**

ISO 20263

**Microbeam analysis — Analytical
electron microscopy — Method
for the determination of interface
position in the cross-sectional
image of the layered materials**

*Analyse par microfaisceaux — Microscopie électronique
analytique — Méthode de détermination de la position
d'interface dans l'image de coupe transversale des matériaux en
couches*

**Second edition
2024-11**



COPYRIGHT PROTECTED DOCUMENT

© ISO 2024

All rights reserved. Unless otherwise specified, or required in the context of its implementation, no part of this publication may be reproduced or utilized otherwise in any form or by any means, electronic or mechanical, including photocopying, or posting on the internet or an intranet, without prior written permission. Permission can be requested from either ISO at the address below or ISO's member body in the country of the requester.

ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Email: copyright@iso.org
Website: www.iso.org

Published in Switzerland